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JUN 9. 3 2006

PATENT Attorney Docket No. IBX-006 (120441/156278)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANT(S):

Chan et al.

SERIAL NO.:

10/645,120

GROUP NO.:

3712

FILING DATE:

August 21, 2003

EXAMINER:

Not yet assigned

TITLE:

Supervised Learning in the Presences of Null Data

CERTIFICATE OF FIRST CLASS MAILING UNDER 37 C.F.R. 1.8

I hereby certify that this correspondence, and any document(s) referred to as enclosed herein, is/are being deposited with the United States Postal Service as first class mail, postage prepaid, in an envelope addressed to Mail Stop Amendment, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on this 2/st day of June, 2006.

Lea R. Jayme

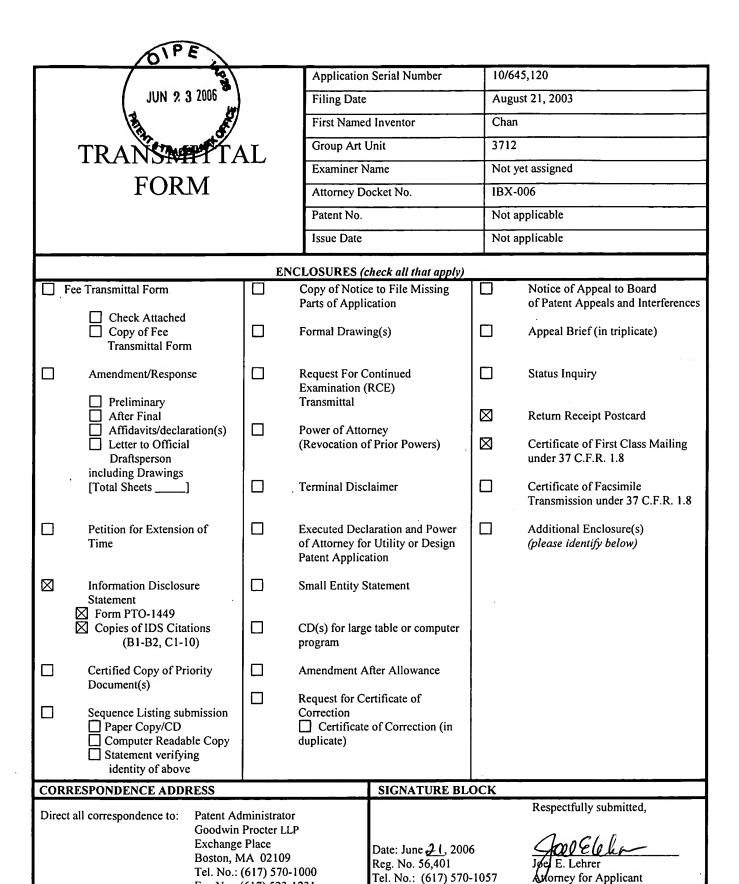
Mail Stop Amendment Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

Submitted herewith are:

- 1. Transmittal Form (1 page);
- 2. Information Disclosure Statement (2 pages);
- 3. Copies of references cited (B1-B2, C1-C10);
- 4. Form PTO 1449 (2 pages); and
- 5. Return-receipt postcard.

VER 9/00



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INFORMATION DISCLOSURE STATEMENT

Sir:

In accordance with the provisions of 37 C.F.R. 1.97 and 1.98, Applicants hereby make of record the patents and publications listed on the accompanying Form PTO-1449, and other information contained herein, for consideration by the Examiner in connection with the examination of the above-identified patent application. In accordance with 37 C.F.R. 1.98(a)(2), only copies of the foreign patent documents and not-patent publications are enclosed.

REMARKS

In accordance with the provisions of 37 C.F.R. 1.97, this statement is being filed (CHECK ONE):

(1)	within three (3) months of the filing date of a national application other than a continued prosecution application under 37 C.F.R. 1.53(d), or within three (3) months of the date of entry of the national stage as set forth in 37 C.F.R. 1.491 in an international application, or before the mailing of the first Office action on the merits, or before the mailing of a first Office action after the filing of a request for continued examination under 37 C.F.R. 1.114; or
(2)	after the period defined in (1) but before the mailing date of a final action or a notice of allowance under 37 C.F.R. 1.311, and
	the requisite Statement is below, OR
	the requisite fee under 37 C.F.R. 1.17(p), namely \$180.00, is included herein, or

Serial No. 10/645,120 Page 2 of 2 after the mailing date of a final action or notice of allowance but before the payment (3) of the issue fee, AND the requisite Statement is below, AND the requisite petition fee under 37 C.F.R. 1.17(p), namely \$180.00 is included herein. It is respectfully requested that each of the patents and publications listed on the attached Form PTO-1449, and other information contained herein, be made of record in this application. **STATEMENT** As required under 37 C.F.R. 1.97(e), Applicant(s), through the undersigned, hereby state either that [check the appropriate space only if either (2) or (3) is checked on the previous page and the Statement is required]: Each item of information contained in the Information Disclosure Statement was • 1. first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of the Information Disclosure Statement; or П 2. No item of information contained in the Information Disclosure Statement was cited in a communication from a foreign patent office in a counterpart foreign application, and, to the knowledge of the person signing this Statement after making reasonable inquiry, no item of information contained in the Information Disclosure Statement was known to any individual designated in 37 C.F.R. 1.56(c) more than three months prior to the filing of the Information Disclosure Statement.

Respectfully submitted,

Date: June <u>M</u>, 2006 Reg. No. 56,401

Information Disclosure Statement

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Boston, Massachusetts 02109

Customer No. 051414

FORM	PTO •	1449	<u> </u>	га	TORNEY	DOCKE	T NO · II	3X-006			
FORM PTO - 1449 INFORMATION DISCUSSIVE					ATTORNEY DOCKET NO.: IBX-006 APPLICANT(S): Chan et al.						
STATE	MENT		l	SERIAL NO.: 10/645,120							
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	10	, , , , , ,		FILING DATE: 08/21/03 GROUP: 3712							
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EXAM. INIT.		DOCUMENT NUMBER	DATE	NAME CLASS SUB FILING DA CLASS APPROPRI							
	A1	A1 5,467,883 11/21/95 Frye et al. 216 60 11/27/				7/93					
	A2	5,559,690	9/24/96	Keeler et	al.		364	164	9/16/94		
	A3	5,654,903	8/5/97	Reitman e	et al.		364	551.01	51.01 11/7/95		
	A4	5,740,033	4/14/98	Wassick e	t al.		364	149	10/13/92		
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	A9	6,212,438	04/03/01	Reine, Fra	nk		700	48 04/23/98		3/98	
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	B1	WO 01/57605	8/9/01	WO	GO5B	13/04	1/11/01	N Y		Y	
	B2	DE196 37 917 A1	3/19/98	DE	GO5B	13/04	9/17/96	Y		N	
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,	C1	C1 Card et al., "Dynamic Neural Control for Plasma Etch Process," <u>IEEE Transactions on Neural Networks</u> , (1997).									
	C2	C2 Hatzipantelis et al., "Comparing Hidden Markov Models with Artificial Neural Network Architectures for Condition Monitoring Applications," <u>Artificial Neural Networks</u> , 26-28, Conference Publication No. 409 (June 1995).									
	C3	Kim et al., "Intelligent Control of Via Formation by Photosensitive BCB for MCM-L/D Applications," <u>IEEE Transactions on Semiconductor Manufacturing</u> , 12:503 (1999).									

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		APPLICANT(S): Chan et al.						
STATE	MENT/	SERIAL NO.: 10/645,120						
		JUN 9. 3 2006 FILING DATE: 08/21/03 GROUP: 3712						
		THER ART, JOURNAL ARTICLES, ETC.						
EXAM. INIT.	EXAM. OTHER DOCUMENTS: (Including Author, Title, Date, Relevant Pages, Place of Publication)							
	C4	Konstantopoulos et al., "Controllers with Diagnostic Capabilities. A Neural Network Implementation. Journal of Intelligent and Robotic Systems," Department of Electrical Engineering, University of Notre Dame, IN 12: 197-228 (1995).						
-	C5	Lada et al., "A Wavelet-Based Procedure for Process Fault Detection," (September 17, 2001).						
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,	C7	Rietman et al., "A System Model for Feedback Control and Analysis of Yield: A Multistep Process Model of Effective Gate Length, Poly Line Width, and IV Parameters," <u>IEEE</u> (2001).						
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	C9	Smyth et al., "Hidden Markov Models an Neural Networks for Fault detection in Dynamic Systems," California Institute of Technology (1993).						
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